



SDI FINAL EVALUATION FORM 1.1

PART 1:

Journal Name:	Physical Science International Journal
Manuscript Number:	Ms_PSIJ_29024
Title of the Manuscript:	Influence of Annealing Temperature on the Physical Properties of Polycrystalline Cu ₂ SnSe ₃ Thin Films Prepared by Thermal Vacuum Evaporation Technique
Type of Article:	Original Research Article

PART 2:

FINAL EVALUATOR'S comments on revised paper (if any)	Authors' response to final evaluator's comments
<p>❖ Section 3.2 Energy Dispersive X-Ray Analysis (EDX), Line 6) "Figure 5.26?" change to "Figure 3".</p> <p>❖ Section 3.2 Energy Dispersive X-Ray Analysis (EDX), Title of Figure 3) "Figure 3: EDX spectrum of Cu₂SnSe₃ thin films annealed at 500 °C." change to " Figure 3: EDX spectrum of Cu₂SnSe₃ thin films as-deposited and annealed (at 100, 200, 300, 400 and 500 °C)." or "Figure 3: EDX spectrum of the as-deposited and annealed Cu₂SnSe₃ thin films at 100°C, 200°C, 300°C, 400°C and 500°C."</p> <p>❖ On the other hand I notice that the reference [15] did not exist in the text.</p> <p>Please find enclosed the attached file of: Revised-ms_PSIJ_29024_v1. doc with (All corrections are mentioned in red color).</p>	

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